

## Description

The VSM65N03 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

V<sub>DS</sub> =30V,I<sub>D</sub> =65A

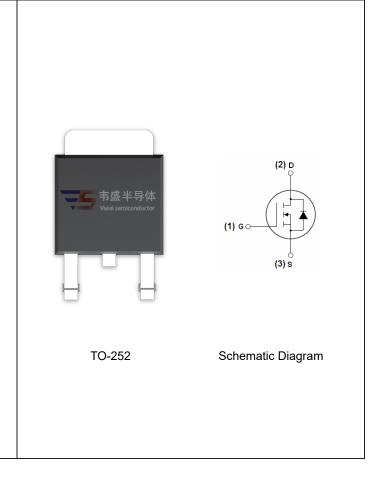
 $R_{DS(ON)}$  <7.0m $\Omega$  @  $V_{GS}$ =10V

 $R_{DS(ON)} < 9.5 \text{m}\Omega$  @  $V_{GS} = 5V$ 

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

### **Application**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM65N03-T2	VSM65N03	TO-252	-	-	-

## Absolute Maximum Ratings (T<sub>c</sub>=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	Vgs	±20	V	
Drain Current-Continuous	I <sub>D</sub>	65	А	
Drain Current-Continuous(T <sub>C</sub> =100 °C)	I <sub>D</sub> (100℃)	46	А	
Pulsed Drain Current	I <sub>DM</sub>	200	А	
Maximum Power Dissipation	P <sub>D</sub>	65	W	
Derating factor		0.43	W/℃	
Single pulse avalanche energy (Note 5)	Eas	150	mJ	
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 175	$^{\circ}$	

### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{ heta JC}$	2.3	°C/W

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# Electrical Characteristics (TC=25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	•		•			
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	30	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)			•			
Gate Threshold Voltage	$V_{GS(th)}$	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA	1	1.5	2.5	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	5.7	7.0	mΩ
Drain-Source On-State Resistance		V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A	-	7.7	9.5	
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =20A	20	-	-	S
Dynamic Characteristics (Note4)	•		•			•
Input Capacitance	C <sub>lss</sub>	\/ -45\/\/ -0\/	-	1400	-	PF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ =15V, $V_{GS}$ =0V, F=1.0MHz	-	205	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F-1.UIVIDZ	-	177	-	PF
Switching Characteristics (Note 4)	•		•			
Turn-on Delay Time	t <sub>d(on)</sub>		-	9	-	nS
Turn-on Rise Time	t <sub>r</sub>	V <sub>DD</sub> =5V,I <sub>D</sub> =20A	-	8	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10 $V$ , $R_{GEN}$ =6 $\Omega$	-	28	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	5	-	nS
Total Gate Charge	$Q_g$	\/ -15\/  -201	-	32.3	-	nC
Gate-Source Charge	$Q_{gs}$	$V_{DS}=15V,I_{D}=20A,$ $V_{GS}=10V$	-	4.9	-	nC
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> -10V	-	6.9	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	-	0.85	1.2	V
Diode Forward Current (Note 2)	Is		-	-	65	Α
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, I <sub>F</sub> = 20A	-	-	27	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs <sup>(Note3)</sup>	-	-	20	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

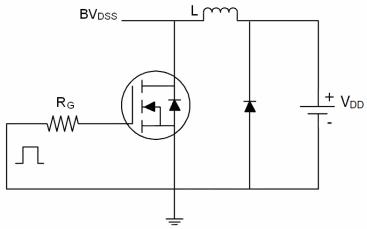
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- 3. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V<sub>DD</sub>=15V,V<sub>G</sub>=10V,L=0.5mH,Rg=25 $\Omega$

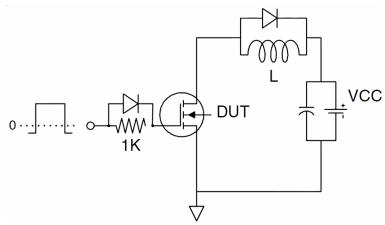


## **Test Circuit**

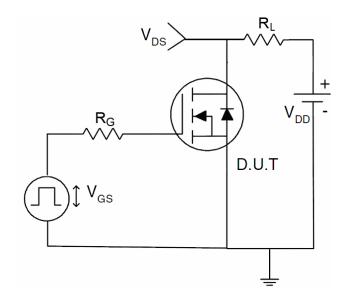
# 1) E<sub>AS</sub> Test Circuits



# 2) Gate Charge Test Circuit

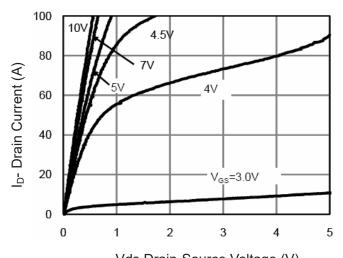


## 3) Switch Time Test Circuit

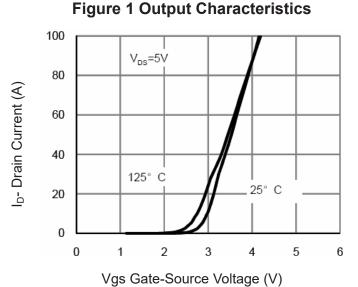




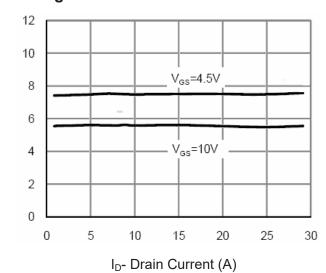
## **Typical Electrical and Thermal Characteristics (Curves)**



Vds Drain-Source Voltage (V)



**Figure 2 Transfer Characteristics** 



Rdson On-Resistance Normalized

Figure 3 Rdson- Drain Current

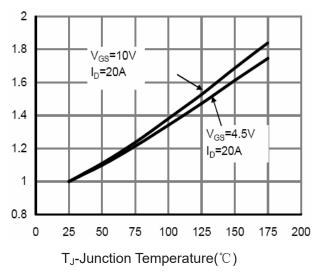


Figure 4 Rdson-JunctionTemperature

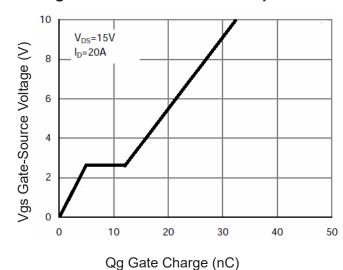


Figure 5 Gate Charge

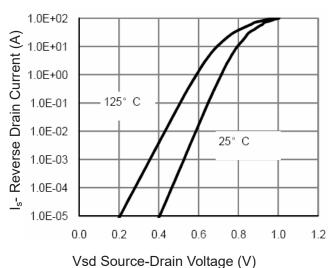


Figure 6 Source- Drain Diode Forward



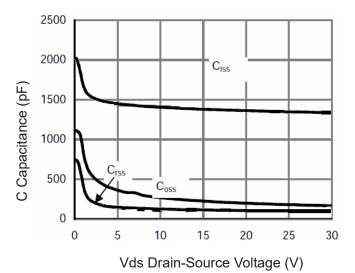


Figure 7 Capacitance vs Vds

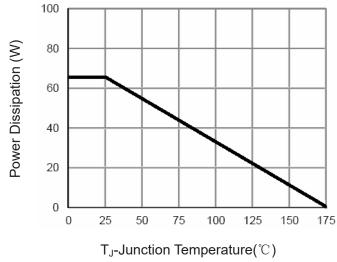
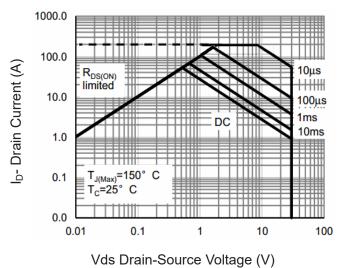


Figure 9 Power De-rating



**Figure 8 Safe Operation Area** 

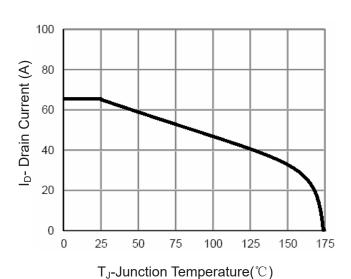
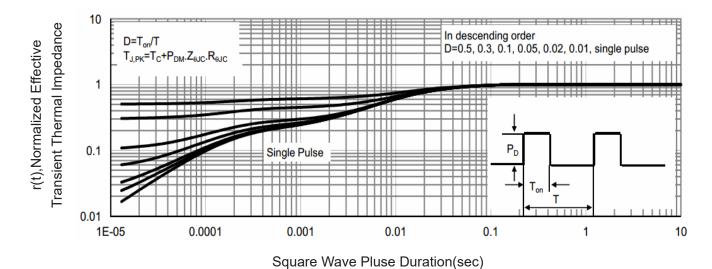


Figure 10 ID Current- Junction Temperature



**Figure 11 Normalized Maximum Transient Thermal Impedance**